

Mechanical Shock

Solderability

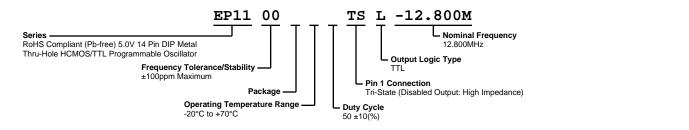
Vibration

**Resistance to Soldering Heat** 

**Resistance to Solvents** 

**Temperature Cycling** 





| ELECTRICAL SPECIFICA              | ELECTRICAL SPECIFICATIONS  |  |  |
|-----------------------------------|--|--|--|
| Nominal Frequency                 | 12.800MHz  |  |  |
| Frequency Tolerance/Stability     | ±100ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range,Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration) |  |  |
| Aging at 25°C                     | ±5ppm/year Maximum   |  |  |
| Operating Temperature Range       | -20°C to +70°C   |  |  |
| Supply Voltage                    | 5.0Vdc ±10%  |  |  |
| Input Current                     | 45mA Maximum (Unloaded)  |  |  |
| Output Voltage Logic High (Voh)   | 2.4Vdc Minimum (IOH = -16mA)   |  |  |
| Output Voltage Logic Low (Vol)    | 0.4Vdc Maximum (IOL = +16mA)   |  |  |
| Rise/Fall Time                    | 4nSec Maximum (Measured at 0.8Vdc to 2.0Vdc)   |  |  |
| Duty Cycle                        | 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load)  |  |  |
| Load Drive Capability             | 10TTL Load Maximum   |  |  |
| Output Logic Type                 | TTL  |  |  |
| Pin 1 Connection                  | Tri-State (Disabled Output: High Impedance)  |  |  |
| Pin 1 Input Voltage (Vih and Vil) | +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output.  |  |  |
| Standby Current                   | 50μA Maximum (Pin 1 = Ground)  |  |  |
| Disable Current                   | 30mA Maximum (Pin 1 = Ground)  |  |  |
| Peak to Peak Jitter (tPK)         | 100pSec Maximum, 50pSec Typical  |  |  |
| RMS Period Jitter (tRMS)          | 13pSec Maximum, 8pSec Typical  |  |  |
| Start Up Time                     | 10mSec Maximum   |  |  |
| Storage Temperature Range         | -55°C to +125°C  |  |  |
| ENVIRONMENTAL & MEC               | HANICAL SPECIFICATIONS   |  |  |
| Fine Leak Test                    | MIL-STD-883, Method 1014, Condition A  |  |  |
| Gross Leak Test                   | MIL-STD-883, Method 1014, Condition C  |  |  |
| Lead Integrity                    | MIL-STD-883, Method 2004   |  |  |
|                                   |  |  |  |

MIL-STD-202, Method 213, Condition C

MIL-STD-883, Method 2007, Condition A

MIL-STD-202, Method 210

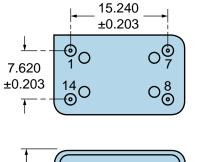
MIL-STD-202, Method 215 MIL-STD-883, Method 2003

MIL-STD-883, Method 1010

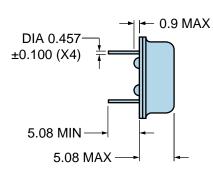
# EP1100TSL-12.800M



### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**

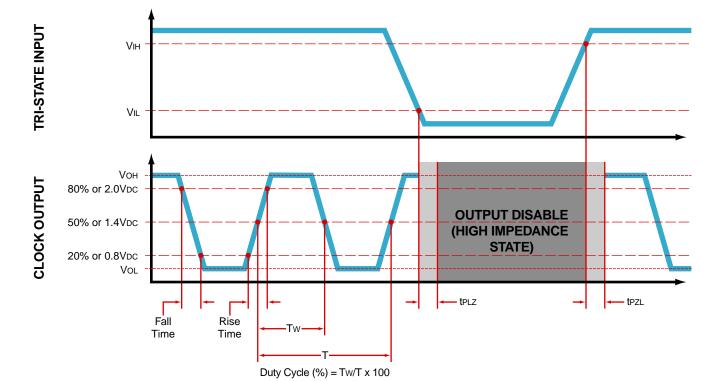






| PIN  | CONNECTION  |
|------|---|
| 1    | Tri-State (High<br>Impedance)   |
| 7    | Ground/Case Ground  |
| 8    | Output  |
| 14   | Supply Voltage  |
| LINE | MARKING   |
| 1    | ECLIPTEK  |
| 2    | EP11TS<br>EP11=Product Series   |
| 3    | 12.800M   |
| 4    | XXYZZ<br>XX=Ecliptek Manufacturing<br>Code<br>Y=Last Digit of the Year<br>ZZ=Week of the Year |

**OUTPUT WAVEFORM & TIMING DIAGRAM** 

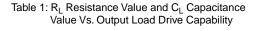


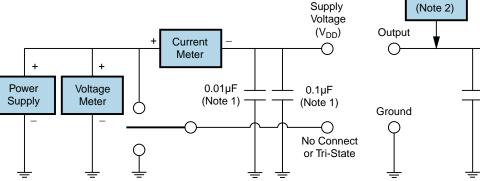
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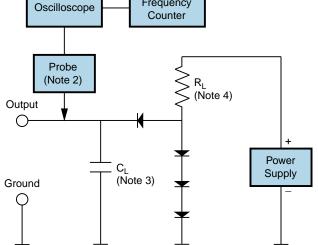


### **Test Circuit for TTL Output**

| Output Load<br>Drive Capability | R <sub>L</sub> Value<br>(Ohms) | C <sub>L</sub> Value<br>(pF) |
|---------------------------------|--------------------------------|------------------------------|
| 10TTL                           | 390                            | 15                           |
| 5TTL                            | 780                            | 15                           |
| 2TTL                            | 1100                           | 6                            |
| 10LSTTL                         | 2000                           | 15                           |
| 1TTL                            | 2200                           | 3                            |







Frequency

Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $C_L$  includes sum of all probe and fixture capacitance.

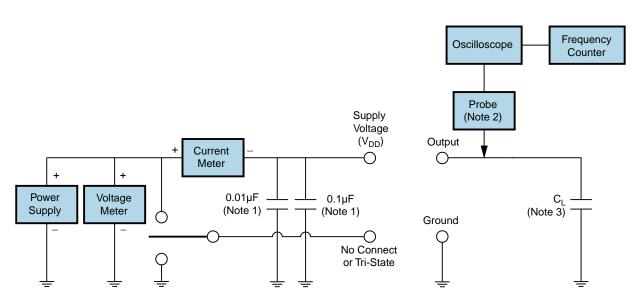
Note 4: Resistance value RL is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.

Note 5: All diodes are MMBD7000, MMBD914, or equivalent.

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### **Test Circuit for CMOS Output**



Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\dot{C}_1$  includes sum of all probe and fixture capacitance.



## **Recommended Solder Reflow Methods**

EP1100TSL-12.800M



### High Temperature Solder Bath (Wave Solder)

| $T_s$ MAX to $T_L$ (Ramp-up Rate)                | 3°C/second Maximum   |
|--|--|
| Preheat  |  |
| - Temperature Minimum (T <sub>s</sub> MIN)       | 150°C  |
| - Temperature Typical (T <sub>s</sub> TYP)       | 175°C  |
| - Temperature Maximum (T <sub>s</sub> MAX)       | 200°C  |
| - Time (t <sub>s</sub> MIN)                      | 60 - 180 Seconds   |
| Ramp-up Rate (T⊾ to T <sub>P</sub> )             | 3°C/second Maximum   |
| Time Maintained Above:                           |  |
| - Temperature (T∟)                               | 217°C  |
| - Time (t∟)                                      | 60 - 150 Seconds   |
| Peak Temperature (T <sub>P</sub> )               | 260°C Maximum for 10 Seconds Maximum   |
| Target Peak Temperature (T <sub>P</sub> Target)  | 250°C +0/-5°C  |
| Time within 5°C of actual peak (t <sub>p</sub> ) | 20 - 40 seconds  |
| Ramp-down Rate                                   | 6°C/second Maximum   |
| Time 25°C to Peak Temperature (t)                | 8 minutes Maximum  |
| Moisture Sensitivity Level                       | Level 1  |
| Additional Notes                                 | Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option. |
|  |  |



## **Recommended Solder Reflow Methods**

EP1100TSL-12.800M



### Low Temperature Infrared/Convection 185°C

| •   |   |
|---|---|
| T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)         | 5°C/second Maximum  |
| Preheat   |   |
| - Temperature Minimum (T <sub>s</sub> MIN)                  | N/A   |
| <ul> <li>Temperature Typical (T<sub>s</sub> TYP)</li> </ul> | 150°C   |
| <ul> <li>Temperature Maximum (T<sub>s</sub> MAX)</li> </ul> | N/A   |
| - Time (t <sub>s</sub> MIN)                                 | 60 - 120 Seconds  |
| Ramp-up Rate (T⊾ to T <sub>P</sub> )                        | 5°C/second Maximum  |
| Time Maintained Above:                                      |   |
| - Temperature (T∟)  | 150°C   |
| - Time (t∟)   | 200 Seconds Maximum   |
| Peak Temperature (T <sub>P</sub> )                          | 185°C Maximum   |
| Target Peak Temperature (T <sub>P</sub> Target)             | 185°C Maximum 2 Times   |
| Time within 5°C of actual peak ( $t_p$ )                    | 10 seconds Maximum 2 Times  |
| Ramp-down Rate  | 5°C/second Maximum  |
| Time 25°C to Peak Temperature (t)                           | N/A   |
| Moisture Sensitivity Level                                  | Level 1   |
| Additional Notes  | Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option. |
|   |   |



# **Recommended Solder Reflow Methods**

EP1100TSL-12.800M



### Low Temperature Solder Bath (Wave Solder)

| T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate) | 5°C/second Maximum   |  |
|---|--|--|
| Preheat   |  |  |
| - Temperature Minimum (Ts MIN)                      | N/A  |  |
| - Temperature Typical (T <sub>s</sub> TYP)          | 150°C  |  |
| - Temperature Maximum (T <sub>s</sub> MAX)          | N/A  |  |
| - Time (t <sub>s</sub> MIN)                         | 30 - 60 Seconds  |  |
| Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )    | 5°C/second Maximum   |  |
| Time Maintained Above:                              |  |  |
| - Temperature (T∟)                                  | 150°C  |  |
| - Time (t∟)   | 200 Seconds Maximum  |  |
| Peak Temperature (T <sub>P</sub> )                  | 245°C Maximum  |  |
| Target Peak Temperature (T <sub>P</sub> Target)     | 245°C Maximum 1 Time / 235°C Maximum 2 Times   |  |
| Time within 5°C of actual peak (t <sub>P</sub> )    | 5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times  |  |
| Ramp-down Rate                                      | 5°C/second Maximum   |  |
| Time 25°C to Peak Temperature (t)                   | N/A  |  |
| Moisture Sensitivity Level                          | Level 1  |  |
| Additional Notes                                    | Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option. |  |

#### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

#### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)